



Basic X-ray experimental techniques - spectroscopy

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Suggested readings (books)



[1] David Attwood, Anne Sakdinawat, (2017). *X-Rays and Extreme Ultraviolet Radiation: Principles and Applications*. Cambridge University Press.

[2] Philip Willmott, (2011). *An introduction to synchrotron radiation: techniques and applications*. John Wiley & Sons, Ltd.

[3] Frank de Groot, Akio Kotani, (2008). Core Level Spectroscopy of Solids. CRC Press.

[4] Grant Bunker, (2010). *Introduction to XAFS: A Practical Guide to X-Ray Absorption Fine Structure Spectroscopy*, Cambridge University Press.

[5] Jeroen A. van Bokhoven, Carlo Lamberti, editors, (2015). *X-Ray Absorption and X-Ray Emission Spectroscopy: Theory and Applications*. John Wiley & Sons, Inc.

Terminology

- **XPS:** X-ray Photolectron Spectroscopy is a technique to probe electronic structure of the occupied orbitals/bands, which provide surface sensitive (few nm) information on chemical composition of materials and their valence state structure
- **ARPES:** Angle **R**esolved **P**hoto**E**lectron **S**pectroscopy is a technique to probe dispersion relation of valence electrons
- **XAS:** X-ray Absorption Spectroscopy is a technique to probe electronic structure of unoccupied orbital/bands, which provide bulk sensitive (few microns) element selective information on local atomic structure
- **XES:** X-ray Emission Spectroscopy is a technique to probe electronic structure of the occupied orbitals/bands, which provide bulk sensitive (few microns) element selective information on charge, spin and valence band density of states
- **RIXS:** Resonant Inelastic X-ray Scattering is a photon-in photon-out spectroscopy technique to probe electronic excitations resolved in energy and momentum

Outline



- 1. Introduction to core level X-ray spectroscopy
- 2. X-ray absorption spectroscopy and dichroism
- 3. X-ray photoelectron spectroscopy and its angular dependence
- 4. X-ray fluorescence and emission spectroscopy
- 5. Resonant inelastic X-ray scattering and related methods
- 6. Summary





Spectroscopy probes the dependence of transmission/absorption of photons by matter as a function of incident photon energy. Absorption process may be probed also by probing the intensity of secondary particles, such as fluorescence photons and Auger/photoelectrons.

X-ray fluorescense and Auger emission



Information depth



few microns

XES, RIXS, etc. Fluorescence XAS Probing depth of X-ray spectroscopy depends on the particles probed. In case of the detection of photons it is of the order of microns to millimeters, while in the case of electrons it is in the order nanometers



few nm

XPS (ARPES) Electron Yield XAS

Electronic structure of matter



Corel level X-ray spectroscopy



Empty

Valence

Eva hv' *Fixed photon energy Variable photon energy*

Core

X-ray absorption spectroscopy



photon-in



photon-out

Strant.

electron-out





Element	K 1s	L ₁ 2s	$L_2 2p_{1/2}$	L ₃ 2p _{3/2}
1 H	13.6			LBN/Patronetics
2 He	24.6*			Center for X-Ray Optics and Advanced Light Source
3 Li	54.7*		X -	RAY DATA
4 Be	111.5*			BOOKLET
5 B	188*		Alber David Eric G Mades	f Thompson Ingolf Lindau I Attwood Planetta JolfAson Arthur Robinson Size Howells James Scofield
6 C	284.2*		Kings Jamos Jeffre	g Je Kim James Underwoe Rirz Dougts Vaughar y Kortright Gwyn Williams Herman Wissick
7 N	409.9*	37.3*		January 2001 January Robins Values Labourory Consump of Janlarma
8 O	543.1*	41.6*	~	Romania (Ch.1973) each nao nachartach an ant le din U.I. Angusteach Annag under Cartraintes Dit ad 24 Addresse
9 F	696.7*			
10 Ne	870.2*	48.5*	21.7*	21.6*
11 Na	1070.8†	63.5†	30.65	30.81
12 Mg	1303.0†	88.7	49.78	49.50
13 Al	1559.6	117.8	72.95	72.55
14 Si	1839	149.7*b	99.82	99.42
15 P	2145.5	189*	136*	135*
16 S	2472	230.9	163.6*	162.5*
17 Cl	2822.4	270*	202*	200*
18 Ar	3205.9*	326.3*	250.6†	248.4*
19 K	3608.4*	378.6*	297.3*	294.6*
20 Ca	4038.5*	438.4†	349.7†	346.2†
21 Sc	4492	498.0*	403.6*	398.7*
22 Ti	4966	560.9†	460.2†	453.8†

Absorption crosssection is proportional to density of unoccupied electronic states at the energy defined by the energy and momentum conservation principles

Binding energy probed in XAS is characteristic for element/orbital. As such the method can be used as element and symmetry selective probe of **unoccupied electronic states**

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X-ray Free Electron Lasers - XFELs

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X-ray absorption experiment



Absorption measured by

transmission

$$I_1 = I_0 e^{-\mu x}$$

 $\frac{electron \ yield \ / \ fluorescence}{I_f \sim I_0 \mu} \qquad I_f \sim I_0 \mu$

XAS can be probed using energy dependence of:

- transmission
- fluorescence
- electron yield



 \rightarrow absorption spectrum



X-ray absorption near edge structure



K absorption edge of *V* compounds of different local structure and *V* oxidation state



Sensitive to electronic occupation

Sensitive to local symmetry & hybridization

Angular and polarization dependence

X-ray linear dichroism (XLD)

Dichroism: the difference in spectral shape observed at distinct orientation of photon polarization with respect to crystal/molecule orientation

Selective probe of structural anisotropy



source: [2]

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X-ray photoelectron spectroscopy



photon-in



photon-out

State by

electron-out



XPS principle





X-ray photoelectron spectroscopy probes the details of (occupied) electronic band structure with **surface sensitivity** and **element selectivity**

Probing depth depends on kinetic energy of photoelectron, E_e , that is dependen on incident photon energy, hv

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source: [2]

XPS applications



Determination of band gap in semiconductors and superconductors

XPS spectra at temperature above and below the superconducting transition in V_3 Si show the shift of valence band maximum with respect to Fermi level

Modern XPS setup



source: [2]

Hemispherical analyzer combined with 2D pixel detector allow for simultaneous probing of energy and angle of emission (angular momentum) of photoelectrons

URANOS at SOLARIS



https://www.youtube.com/watch?v=jkbwOVWtHl8

Angle resolved photoemission (ARPES)

source: [2]



Figure 7.52 Schematic diagram of an angular-resolved photoelectron experiment, including the possible experimental variables. Those relating to the incident beam are suffixed with L, while those relating to the electron are suffixed with e. The unit vector $\hat{\mathbf{e}}_L$ is a polarization vector. The angles are normally referenced to a high-symmetry axis of the crystal.



Energy distribution curves (EDC) Momentum distribution curves (MDC)

Dispersion of electronic band structure, i.e. the dependence of electron binding energy on momentum, E(k) can be probed in three directions of the reciprocal space

ARPES example – topological insulators



Nonmagnetic impurities shift Dirac point towards Fermi surface Magnetic impurities open energy gap, i.e. destroy topologically protected surface states

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X-ray emission spectroscopy



photon-in



photon-out



electron-out





X-ray Free Electron Lasers - XFELs





Energy resolution XRF (silicon detector): ~120eV XES (crystal analyzer): ~1eV background free

Non-destructive probe of chemical composition, effective spin, and valence band structure

Kβ emission spectroscopy

P.Glatzel & U.Bergmann, Coord. Chem. Rev. 249, 65 (2005)



X-ray emission spectra probed with 1 eV resolution show a splitting of $K\beta$ resonance (left) and allow to probe valence band structure (right). The former is sensitive to spin state of the probed element in the sample, while the *latter to the next* neighbour type and distance

Element selective probe of spin state and ligand structure



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Resonant inelastic X-ray scattering



photon-in

human

photon-out



electron-out



RIXS plane

P.Glatzel & U.Bergmann, Coord. Chem. Rev. 249, 65 (2005)

RIXS probes how X-ray *emission intensity* dependes on incident X-ray energy. A typical 2D spectrum is pletted as a function of Energy transfer (or final state energy), which is the difference between Energy of incident and emitted photon

RIXS is especially usefull to probe resonant excitations in strongly correlated materials



X-ray Free Electron Lasers - XFELs

RIXS plane

Fluorescence detected absorption, i.e. constant energy transfer (CET)

Three distinct types of line-scans (spectra) may be extracted from 2D RIXS plane



P.Glatzel & U.Bergmann, Coord. Chem. Rev. 249, 65 (2005)

High energy resolution fluorescence detected X-ray absorption (HERFD-XAS), i.e. constant emission energy (CEE)

Final states of emission or resonant scattering (X-ray Raman), i.e. constant incydent energy (CIE)

HERFD-XAS



Background free detection and sharpening of absorption spectra (beyond that of life-time broadening)

X-ray Raman scattering (XRS)





high energy transfer features provide access to binding energies in the range of soft X-rays, but probed with (two) hard X-ray photons

→ XAS-like bulk sensitive probe of soft matter



Summary



What kind of questions can be answered using X-ray spectroscopy:

- What is the chemical composition of the sample?
- What is the local atomic structure of the absorbing element (symmetry, type and distance of next neighbor, distortions)?
- What is the spin and valence state of the probed element?
- What is the valence band structure (dispersion, DOS, bandgap)?

Depending on the type of particles detected (electrons or photons) it provides surface or bulk sensitive information